SN54ALS874B, SN74ALS874B, SN74ALS876A SN74AS874, SN74AS876 DUAL 4-BIT D-TYPE EDGE-TRIGGERED FLIP-FLOPS

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- 3-State Buffer-Type Outputs Drive Bus Lines Directly
- Bus-Structured Pinout
- Choice of True or Inverting Logic
 - SN54ALS874B, SN74ALS874B, SN74AS874 Have True Outputs
 - SN74ALS876A, SN74AS876 Have Inverting Outputs
- Asynchronous Clear
- Package Options Include Plastic Small-Outline (DW) Packages, Plastic (FN) and Ceramic (FK) Chip Carriers, and Standard Plastic (NT) and Ceramic (JT) 300-mil DIPs

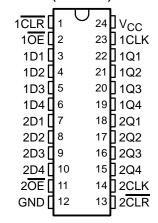
description

These dual 4-bit D-type edge-triggered flip-flops feature 3-state outputs designed specifically as bus drivers. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

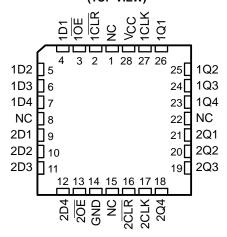
The edge-triggered flip-flops enter data on the low-to-high transition of the clock (CLK) input. The SN54ALS874B, SN74ALS874B, and SN74AS874 have clear ($\overline{\text{CLR}}$) inputs and noninverting Q outputs. The SN74ALS876A and SN74AS876 have preset ($\overline{\text{PRE}}$) inputs and inverting $\overline{\text{Q}}$ outputs; taking $\overline{\text{PRE}}$ low causes the four Q or $\overline{\text{Q}}$ outputs to go low independently of the clock.

The SN54ALS874B is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS874B, SN74ALS876A, SN74AS874, and SN74AS876 devices are characterized for operation from 0°C to 70°C.

SN54ALS874B . . . JT PACKAGE SN74ALS874B, SN74AS874 . . . DW OR NT PACKAGE (TOP VIEW)

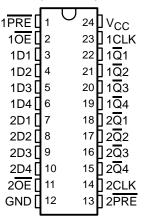


SN54ALS874B . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

SN74ALS876A, SN74AS876 . . . DW OR NT PACKAGE (TOP VIEW)



Function Tables

SN54ALS874B, SN74ALS874B, SN74AS874 (each flip-flop)

	INP	OUTPUT		
Œ	CLR	CLK	D	Q
L	L	Х	Χ	L
L	Н	\uparrow	Н	Н
L	Н	\uparrow	L	L
L	Н	L	Χ	Q_0
Н	Χ	Χ	Χ	Z

SN74ALS876A, SN74AS876 (each flip-flop)

	•		. ,	
	INP	OUTPUT		
OE	PRE	CLK	D	Q
L	L	Х	Х	L
L	Н	\uparrow	Н	L
L	Н	\uparrow	L	Н
L	Н	L	Χ	Q ₀ z
Н	X	X	X	Z

logic symbols†

7

8

9

10

2D1

2D2

2D3

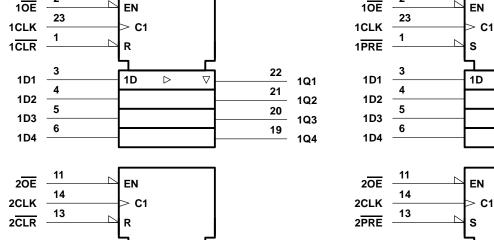
2D4

1D

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SN54ALS874B, SN74ALS874B, SN74AS874

SN74ALS876A, SN74AS876 2 2



18

17

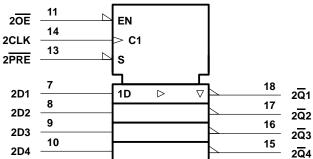
16

2Q1

2Q2

2Q3

2Q4



 \triangleright

 ∇

22

21

20

19

1<u>Q</u>1

1<u>Q</u>2

1<u>Q</u>3

1**Q**4

 ∇



[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the DW, JT, and NT packages.

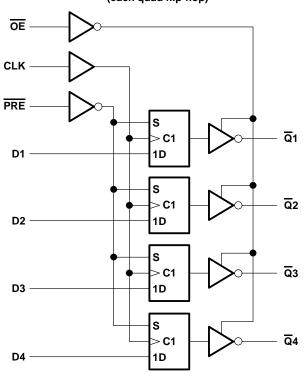
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logic diagrams (positive logic)

SN54ALS874B, SN74ALS874B, SN74AS874 (each quad flip-flop)

OE CLR > C1 D1 1D R > C1 D2 1D R > C1 D3 1D R > C1 D4 1D

SN74ALS876A, SN74AS876 (each quad flip-flop)



Pin numbers shown are for the DW, JT, and NT packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T _A : SN54ALS874B	-55°C to 125°C
SN74ALS874B, SN74ALS876A	0°C to 70°C
Storage temperature range	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

SN54ALS874B, SN74ALS874B, SN74ALS876A SN74AS874, SN74AS876 **DUAL 4-BIT D-TYPE EDGE-TRIGGERED FLIP-FLOPS**

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recommended operating conditions

			SN	54ALS87	′4B	SN74ALS874B SN74ALS876A		UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	
Vсс	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.7			0.8	V
loн	High-level output current				-1			-2.6	mA
loL	Low-level output current				12			24	mA
fclock	Clock frequency		0		25	0		30	MHz
		PRE or CLR low	15			10			
t _W	Pulse duration	CLK high	20			16.5			ns
		CLK low	20			16.5			
	0 · · · · · · · · · · · · · · · · · ·	Data	15			15			ns
t _{su}	su Setup time before CLK↑	PRE or CLR inactive	15			10			
th	Hold time, data after CLK↑		4			0			ns
TA	Operating free-air temperature		-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CO	NDITIONS	SN5	64ALS87	4B		4ALS87 4ALS87		UNIT
					TYP [†]	MAX	MIN	TYP [†]	MAX	
VIK		$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2	2		V _{CC} -2			
Vон	OH V _{CC} = 4.5 V		$I_{OH} = -1 \text{ mA}$	2.4	3.3					V
		VCC = 4.5 V	$I_{OH} = -2.6 \text{ mA}$				2.4	3.2		
\/a:	V _{CC} = 4.5 V		I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
VOL		VCC = 4.5 V	$I_{OL} = 24 \text{ mA}$					0.35	0.5	٧
lozh		$V_{CC} = 5.5 \text{ V},$	$V_0 = 2.7 \text{ V}$			20			20	μΑ
lozL		$V_{CC} = 5.5 \text{ V},$	V _O = 0.4 V			-20			-20	μΑ
lį		$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1			0.1	mA
lін		$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			20			20	μΑ
I _Ι L		$V_{CC} = 5.5 \text{ V},$	V _I = 0.4 V			-0.2			-0.2	mA
IO [‡]		$V_{CC} = 5.5 \text{ V},$	V _O = 2.25 V	-20		-112	-30		-112	mA
			Outputs high		14	21		14	21	
	'ALS874B	V _{CC} = 5.5 V	Outputs low		19	30		19	30	
ICC			Outputs disabled		20	32		20	32	mA
	SN74ALS876A		Outputs high					14	21	
		SN74ALS876A V _{CC} = 5.5 V	Outputs low					18	29	
			Outputs disabled					20	31	

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

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switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C _L : R1 : R2 :	; = 4.5 V = 50 pF, = 500 Ω, = 500 Ω, = MIN to			UNIT
			SN54AL	S874B	SN74AL	S874B	
			MIN	MAX	MIN	MAX	
fmax			25		30		MHz
t _{PLH}	CLK	A O	4	18	4	14	ns
^t PHL	OLK	Any Q	4	16	4	14	115
^t PHL	CLR	Any Q	5	23	5	17	ns
^t PZH	ŌĒ	A O	4	24	4	18	ns
t _{PZL}	OE	Any Q	4	21	4	18	115
^t PHZ	ŌĒ	Any O	2	15	2	10	ns
t _{PLZ}		Any Q	3	22	3	12	1115

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C _L = 50 pF R1 = 500 Ω R2 = 500 Ω T _A = MIN t	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R1 = 500 Ω, R2 = 500 Ω, T_A = MIN to MAX [†] SN74ALS876A	
			MIN	MAX	
f _{max}			30		MHz
^t PLH	CLK	A 5	4	14	ns
^t PHL	CLK	Any Q	4	14	115
^t PHL	PRE	Any Q	6	19	ns
^t PZH		. =	4	18	
^t PZL	ŌĒ	Any Q	4	18	ns
^t PHZ	ŌĒ	Any Q	2	10	ne
^t PLZ	ŬE.	Arily Q	3	13	ns

T For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Operating free-air temperature range, T _A : SN74AS874, SN74AS876	0°C to 70°C
Storage temperature range	-65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



SN54ALS874B, SN74ALS874B, SN74ALS876A SN74AS874, SN74AS876 DUAL 4-BIT D-TYPE EDGE-TRIGGERED FLIP-FLOPS

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recommended operating conditions

			SI	N74AS87	74	SN74AS876		'6	LINUT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vсс	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage		2			2			V
VIL	Low-level input voltage				8.0			8.0	V
ЮН	High-level output current				-15			-15	mA
lOL	Low-level output current				48			48	mA
fclock	Clock frequency		0		125	0		80	MHz
		PRE or CLR low	2			4.5			
t _W	Pulse duration	CLK high	3			6.2			ns
		CLK low	4			6.2			
	Outure these before OLIC	Data	2			4.5			ne
^t su	Setup time before CLK↑	PRE or CLR inactive	4			5			ns
t _h	Hold time, data after CLK↑		1			2			ns
TA	Operating free-air temperature		0		70	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CON	DITIONS	_	74AS87 74AS87		UNIT
				MIN	TYP [†]	MAX	
٧ıK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2	V
VOH		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	I _{OH} = −2 mA	V _{CC} -2			V
		$V_{CC} = 4.5 V,$	$I_{OH} = -15 \text{ mA}$	2.4	3.3		V
VOL		$V_{CC} = 4.5 V,$	$I_{OL} = 48 \text{ mA}$		0.35	0.5	V
lozh		$V_{CC} = 5.5 V,$	V _O = 2.7 V			50	μΑ
lozL		V _{CC} = 5.5 V,	V _O = 0.4 V			-50	μА
II		V _{CC} = 5.5 V,	V _I = 7 V			0.1	mA
lіН		V _{CC} = 5.5 V,	V _I = 2.7 V			20	μΑ
l	D	V F.F.V	\\.			-2	A
¹ı∟	All others	$V_{CC} = 5.5 V$	٧١ = ٣. મ ٧			-0.5	mA
lo [‡]		$V_{CC} = 5.5 V,$	V _O = 2.25 V	-30		-112	mA
			Outputs high		82	133	
	SN74AS874	$V_{CC} = 5.5 V$	Outputs low		92	149	
1			Outputs disabled		100	160	A
ICC	SN74AS876		Outputs high		88	142	mA
		$V_{CC} = 5.5 V$	Outputs low		94	150	
			Outputs disabled		100	160	

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, los.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 4.5$ $C_L = 50 \text{ pF}$ $R1 = 500 \Omega$ $R2 = 500 \Omega$ $T_A = \text{MIN to}$ $SN74A$; ; ; o MAX†	UNIT
			MIN	MAX	1
fmax			125		MHz
t _{PLH}	CLK	A O	3	8.5	ns
^t PHL	CLK	Any Q	4	10.5] "
^t PHL	CLR	Any Q	4	9.5	ns
^t PZH		DE Any Q	2	7	ns
t _{PZL}	OE		3	10.5	115
^t PHZ	ŌĒ	Any Q	2	6	
^t PLZ	1 0	Any Q	2	7.5	ns

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

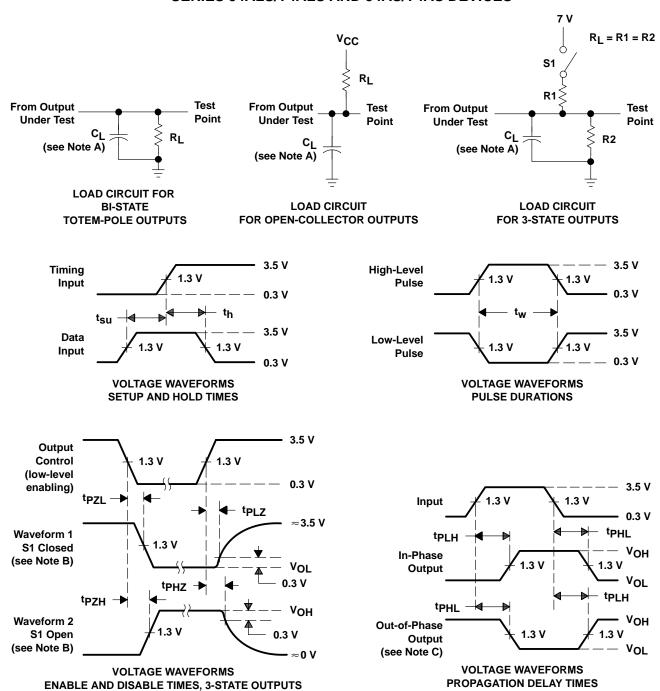
switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C _L = 50 pF R1 = 500 Ω R2 = 500 Ω T _A = MIN t	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$ $C_L = 50 \text{ pF},$ $R1 = 500 \Omega,$ $R2 = 500 \Omega,$ $T_A = \text{MIN to MAX}^{\dagger}$ $SN74AS876$	
			MIN	MAX	
f _{max}			80		MHz
^t PLH	CLK	A G	3	8.5	ns
^t PHL		Any Q	4	10.5	115
^t PHL	PRE	Any $\overline{\mathbb{Q}}$	4	9.5	ns
^t PZH	ŌĒ	, <u>-</u>	2	7	
^t PZL	OE OE	Any Q	3	11	ns
^t PHZ	ŌĒ	Any Q	2	7	
t _{PLZ}	OE .	Ally Q	2	7	ns

T For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

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PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- All input pulses have the following characteristics: PRR \leq 1 MHz, $t_{\Gamma} = t_{f} = 2$ ns, duty cycle = 50%.
- The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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